

<b>Notice of References Cited</b>	Application/Control No. 10/539,158	Applicant(s)/Patent Under Reexamination DETIG ET AL.	
	Examiner Benjamin C. Lee	Art Unit 2612	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,524,758	02-2003	Eberlein et al.	430/11
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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	J	US-			
	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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